



China National Accreditation Service for Conformity Assessment
LABORATORY ACCREDITATION CERTIFICATE
(Registration No. CNAS L23578)

Southchip Semiconductor Technology (Shanghai) Co., Ltd.
Reliability Test Laboratory

(Legal Entity: Southchip Semiconductor Technology (Shanghai) Co., Ltd.)

Room 510/511/501/504, Building 1, No.491, Yindong Road, Pilot Free Trade
Zone, Pudong New Area, Shanghai, China

is accredited in accordance with ISO/IEC 17025: 2017 General Requirements for the Competence of Testing and Calibration Laboratories(CNAS-CL01 Accreditation Criteria for the Competence of Testing and Calibration Laboratories) for the competence to undertake the service described in the schedule attached to this certificate.

The scope of accreditation is detailed in the attached schedule bearing the same registration number as above. The schedule forms an integral part of this certificate.

Effective Date: 2025-07-04

Expiry Date: 2031-07-03

Signed on behalf of China National Accreditation Service for Conformity Assessment

徐朝华

China National Accreditation Service for Conformity Assessment (CNAS) is authorized by Certification and Accreditation Administration of the People's Republic of China (CNCA) to operate the national accreditation schemes for conformity assessment. CNAS is a signatory of the International Laboratory Accreditation Cooperation Mutual Recognition Arrangement (ILAC MRA) and the Asia Pacific Accreditation Cooperation Mutual Recognition Arrangement (APAC MRA).

The validity of the certificate can be checked on CNAS website at <http://www.cnas.org.cn/english/findanaccreditedbody/index.shtml>.

Name: Southchip Semiconductor Technology (Shanghai) Co., Ltd. Reliability Test Laboratory

Address: Room 510/511/501/504, Building 1, No. 491, Yindong Road, Pilot Free Trade Zone, Pudong New Area,
Shanghai, China

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Accreditation Criteria: ISO/IEC 17025:2017 and relevant requirements of CNAS

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SCHEDULE 3 ACCREDITED TESTING SCOPE

№	Test Object	Item/Parameter		Standard or Method	Note	Effective Date
		№	Item/ Parameter			
1	Semiconductor device	1	High Temp , Bias, and Operating Life	Temperature, Bias, and Operating Life JESD22-A108G:2022	Accredited only for: Temperature range: +55 °C ~ +150 °C; Current ≤ 20A; Voltage ≤ 1000V。	2025-07-04
		2	Steady State Temperature Humidity Bias Life Test	Steady State Temperature Humidity Bias Life Test JESD22-A101D.01:2021	Accredited only for bias tested。 Accredited	2025-07-04



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The scope of the accreditation in Chinese remains the definitive version.

№	Test Object	Item/Parameter		Standard or Method	Note	Effective Date
		№	Item/ Parameter			
					only for: Temperature range: +30°C ~ +85°C; Relative humidity range: 60%RH~85%RH; Current ≤ 20A; Voltage ≤ 1000V。	
		3	Preconditioning	Preconditioning Of Nonhermetic Surface Mount Devices Prior to Reliability Testing JEDECJESD22-A113I:2020	Accredited only for: Temperature range: 30°C ~ 150°C; Relative humidity range: 60%RH~85%RH。 Reflow Soldering Temperature 0°C~300°C	2025-07-04



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№	Test Object	Item/Parameter		Standard or Method	Note	Effective Date
		№	Item/ Parameter			
					Do not performed optical microscope and Scanning Acoustic Tomography.	
		4	Accelerated Moisture Resistance - Unbiased Autoclave	Accelerated Moisture Resistance - Unbiased Autoclave JESD22-A102E:2015	Accredited only for: Temperature range: +110 °C~+130 °C; Relative humidity range: 85%RH~100%RH; Air pressure ≤ 230kPa.	2025-07-04
		5	Unbiased Highly Accelerated Stress Test	Accelerated Moisture Resistance - Unbiased HAST JESD22-A118B.01:2021	Accredited only for: Temperature range: +110 °C~+130 °C; Relative humidity	2025-07-04



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№	Test Object	Item/Parameter		Standard or Method	Note	Effective Date
		№	Item/ Parameter			
					range: 85%RH~10 0%RH; Air pressure ≤ 230kPa。	
		6	Steady State Temperature Humidity Unbiased Life Test	Steady State Temperature Humidity Bias Life Test JESD22-A101D.01:2021	Accredited only for Unbias tested: Temperatur e range: +30 °C ~ +85 °C; Relative humidity range: 60%RH~85 %RH。	2025-07-04
		7	Temperature Cycle	Temperature Cycling JESD22-A104F.01:2023	Accredited only for: Temperatur e range: -65 °C~+150 °C; Rising temperature rate: from - 65 °C to + 150 °C within 5	2025-07-04



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№	Test Object	Item/Parameter		Standard or Method	Note	Effective Date
		№	Item/ Parameter			
					minutes; Falling temperature rate: from + 150 °C to -65 °C within 5 minutes。	
		8	Power Temperature Cycle	Power and Temperature Cycling JESD22-A105D:2020	Accredited only for: Temperatur e range: -65 °C~+150 °C; Current ≤ 20A; Voltage ≤ 300V。	2025-07-04
		9	High Temperature Storage Life	High Temperature Storage Life JESD22-A103E.01:2021	Accredited only for: Temperatur e range: +20 °C ~ +200 °C。	2025-07-04
		10	Early Life Failure Rate	Early Life Failure Rate ((ELFR)) AEC-Q100-008 REV-A July 18,2023	Accredited only for: Temperatur e range:+ 55 °C~ +150 °C; Current ≤	2025-07-04



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№	Test Object	Item/Parameter		Standard or Method	Note	Effective Date
		№	Item/ Parameter			
					20A; Voltage ≤ 1000V。	
		11	Highly Accelerated Stress Test	Highly Accelerated Temperature and Humidity Stress Test JESD22-A110E.01:2021	Accredited only for: Temperature range: +110 °C~ +130 °C; Relative humidity range: 85%RH~100%RH; Current ≤ 20A; Voltage ≤ 100V; Air pressure ≤ 230kPa。	2025-07-04



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